Erratum to: Distribution of surfactant ions near the surface of non-aqueous solution gained by angular resolved X-ray photoelectron spectroscopy

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Unfortunately, a misspelling occurred in this paper, both in abstract and in the main text. The word, “generic”, should be corrected to be “genetic”. The correct Abstract is given below:

Abstract Angular resolved X-ray photoelectron spectroscopy (ARXPS) has been applied to obtain the distribution of chemical elements near the surface of non-aqueous solutions containing surfactants. However, such profiles can only yield a quantitative relation between those constituents near the surface regime of sample. With the knowledge of the molar volumes of surfactant and solvent, we have obtained the molar concentration-depth profiles via the molar fraction-depth profiles that were reconstructed by ARXPS with the help of a genetic algorithm. The concentration profiles show detailed distributions of the surfactant ions near the surface, which provide a direct insight into the surface picture of the surfactant solution.

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